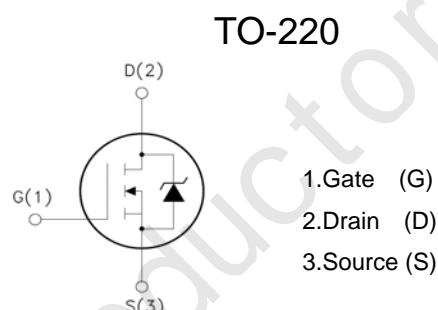
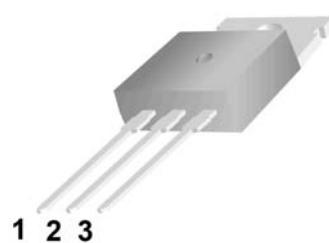


Features:

- Low Intrinsic Capacitances.
- Excellent Switching Characteristics.
- Extended Safe Operating Area.
- Unrivalled Gate Charge : $Q_g = 31\text{nC}$ (Typ.).
- $\text{BVDS}=60\text{V}, I_D=50\text{A}$
- $R_{DS(on)} : 22\text{m}\Omega$ (Max) @ $V_G=10\text{V}$
- 100% Avalanche Tested



Absolute Maximum Ratings* (Tc=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	60	V
I_D	Drain Current	$T_c=25^\circ\text{C}$	50
		$T_c=100^\circ\text{C}$	35.4
V_{GSS}	Gate Threshold Voltage	± 25	V
E_{AS}	Single Pulse Avalanche Energy (note1)	490	mJ
I_{AR}	Avalanche Current (note2)	50	A
P_D	Power Dissipation ($T_c=25^\circ\text{C}$)	120	W
T_j	Junction Temperature(MAX)	150	$^\circ\text{C}$
T_{stg}	Storage Temperature	-55~+150	
T_L	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	

Thermal Characteristics

Symbol	Parameter	Typ.	MAX.	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	-	1.24	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	-	62.5	
$R_{\theta CS}$	Thermal Resistance,Case to Sink	-	0.5	

Electrical Characteristics T_c=25°C unless otherwise noted

Symbol	Parameter	Test Condition	Min.	Typ.	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	ID=250 μA, VGS=0	60	--	--	V
△BV _{DSS} /△T _J	Breakdown Voltage Temperature Coefficient	I _D =250 μA, Reference to 25°C	--	0.06	--	V/°C
IDSS	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V	--	--	1	μA
		V _{DS} =48V, T _c =125 °C			10	μA
IGSSF	Gate-body leakage Current, Forward	V _{GS} =+25V, V _{DS} =0V	--	--	100	nA
IGSSR	Gate-body leakage Current, Reverse	V _{GS} =-25V, V _{DS} =0V	--	--	-100	nA

On Characteristics

V _{GS(th)}	Date Threshold Voltage	I _D =250uA, V _{DS} =V _{GS}	2	--	4	V
R _{DS(on)}	Static Drain-Source On-Resistance	I _D =25A, V _{GS} =10V	--	--	0.022	Ω

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0, f=1.0MHz	--	1180	1540	pF
C _{oss}	Output Capacitance		--	440	580	pF
C _{rss}	Reverse Transfer Capacitance		--	65	90	pF

Switching Characteristics

T _{d(on)}	Turn-On Delay Time	V _{DD} =250V, ID=25A RG=25 Ω (Note 3,4)	--	15	40	nS
T _r	Turn-On Rise Time		--	105	220	nS
T _{d(off)}	Turn-Off Delay Time		--	60	130	nS
T _f	Turn-Off Fall Time		--	65	140	nS
Q _g	Total Gate Charge	V _{DS} =400, V _{GS} =10V, ID=25A (Note 3,4)	--	31	41	nC
Q _{gs}	Gate-Source Charge		--	8	--	nC
Q _{gd}	Gate-Drain Charge		--	13	--	nC

Drain-Source Diode Characteristics and Maximum Ratings

I _S	Maximum Continuous Drain-Source Diode Forward Current	--	--	50	A	
I _{SM}	Maximum Plated Drain-Source Diode Forward Current	--	--	200	A	
V _{SD}	Drain-Source Diode Forward Voltage	Id=25A	--	--	1.5	V
trr	Reverse Recovery Time	I _S =25A, V _{GS} =0V	--	52	--	nS
Qrr	Reverse Recovery Charge	di _F /dt=100A/ μ s (Note 3)	--	75	--	μ C

*Notes 1, L=9.3mH, IAS=50A, VDD=50V, RG=25Ω, Starting TJ =25°C

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%

4, Essentially Independent of Operating Temperature

Typical Characteristics

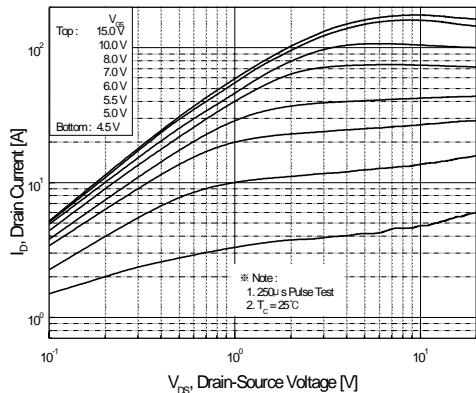


Figure 1. On-Region Characteristics

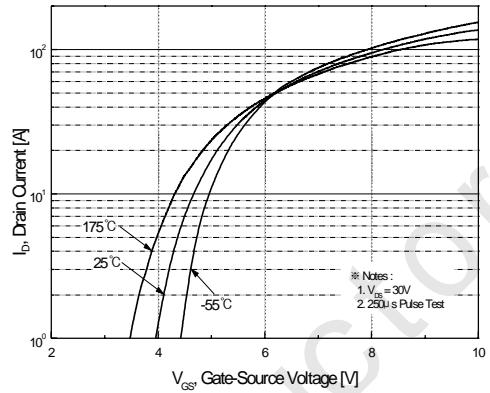


Figure 2. Transfer Characteristics

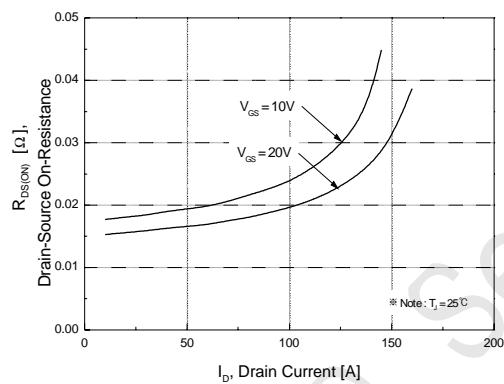


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

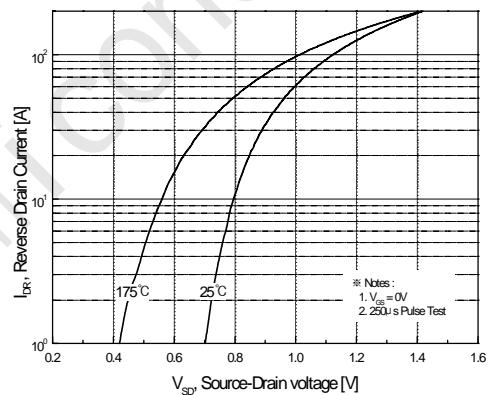


Figure 4. Body Diode Forward Voltage
Variation vs. Source Current
and Temperature

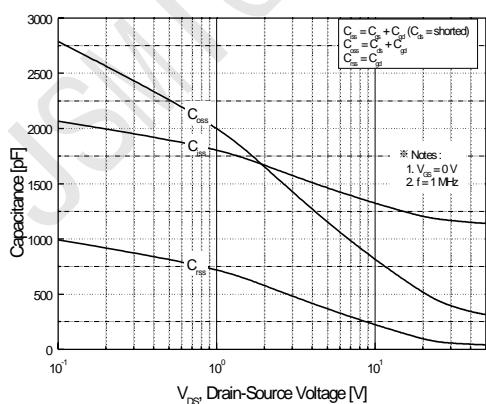


Figure 5. Capacitance Characteristics

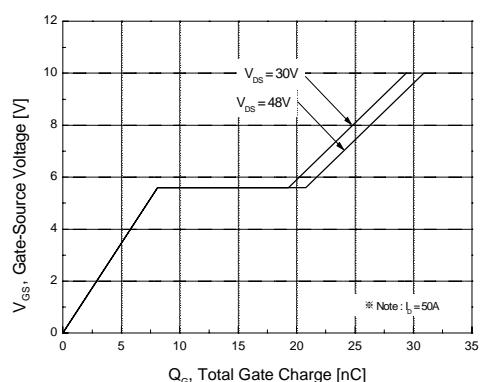
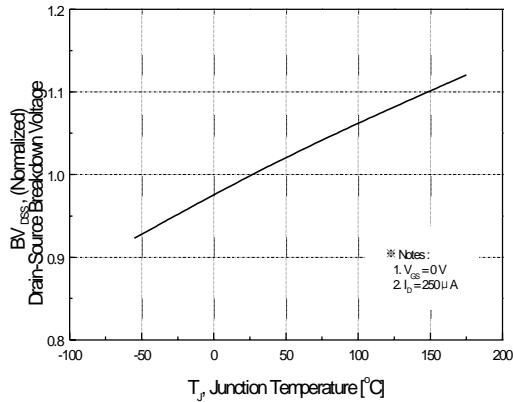
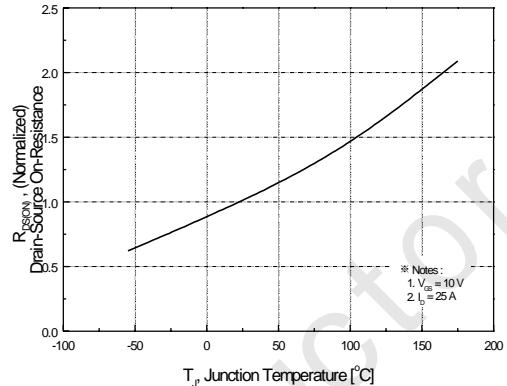


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)



**Figure 7. Breakdown Voltage Variation
vs. Temperature**



**Figure 8. On-Resistance Variation
vs. Temperature**

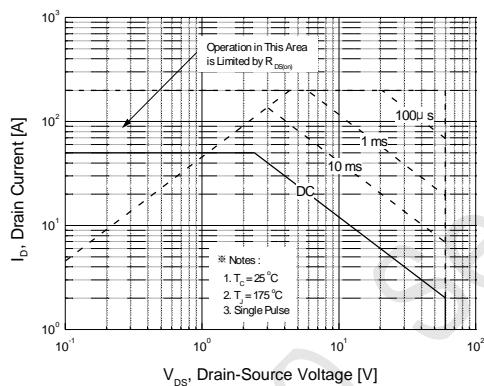
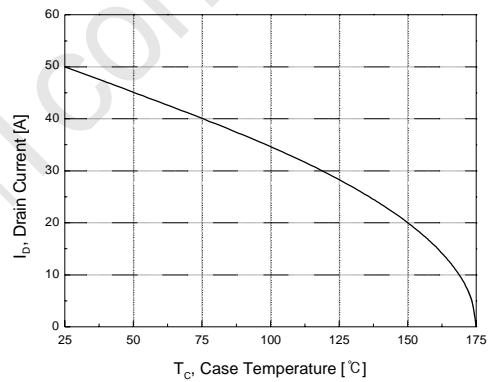


Figure 9. Maximum Safe Operating Area



**Figure 10. Maximum Drain Current
vs. Case Temperature**

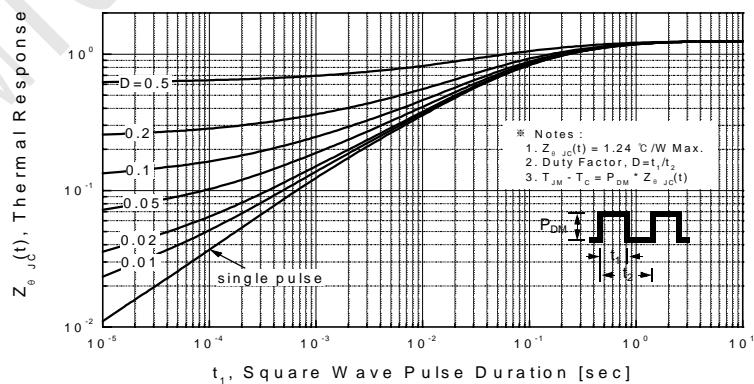
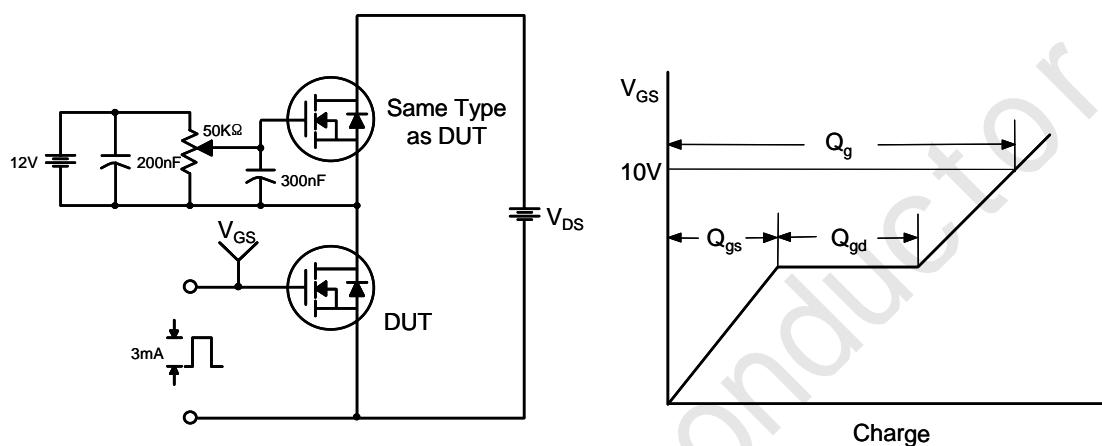


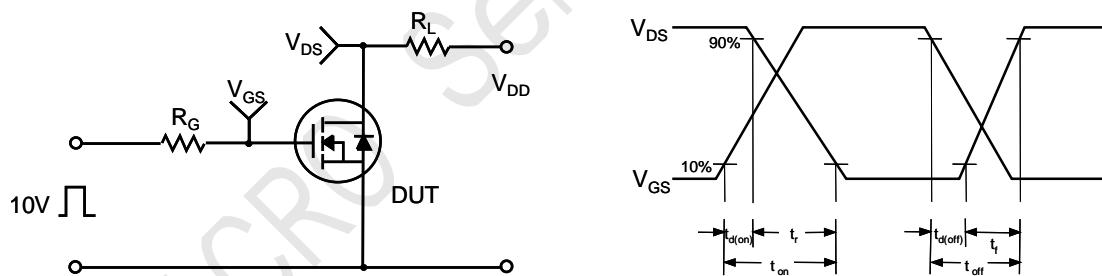
Figure 11. Transient Thermal Response Curve

Typical Characteristics (Continued)

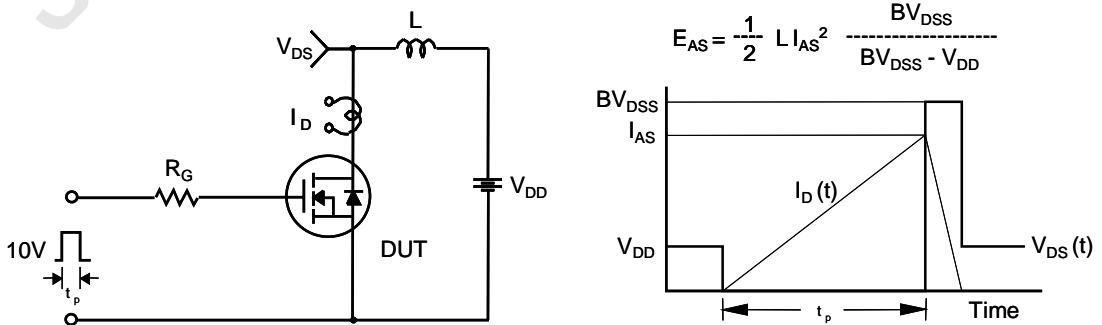
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

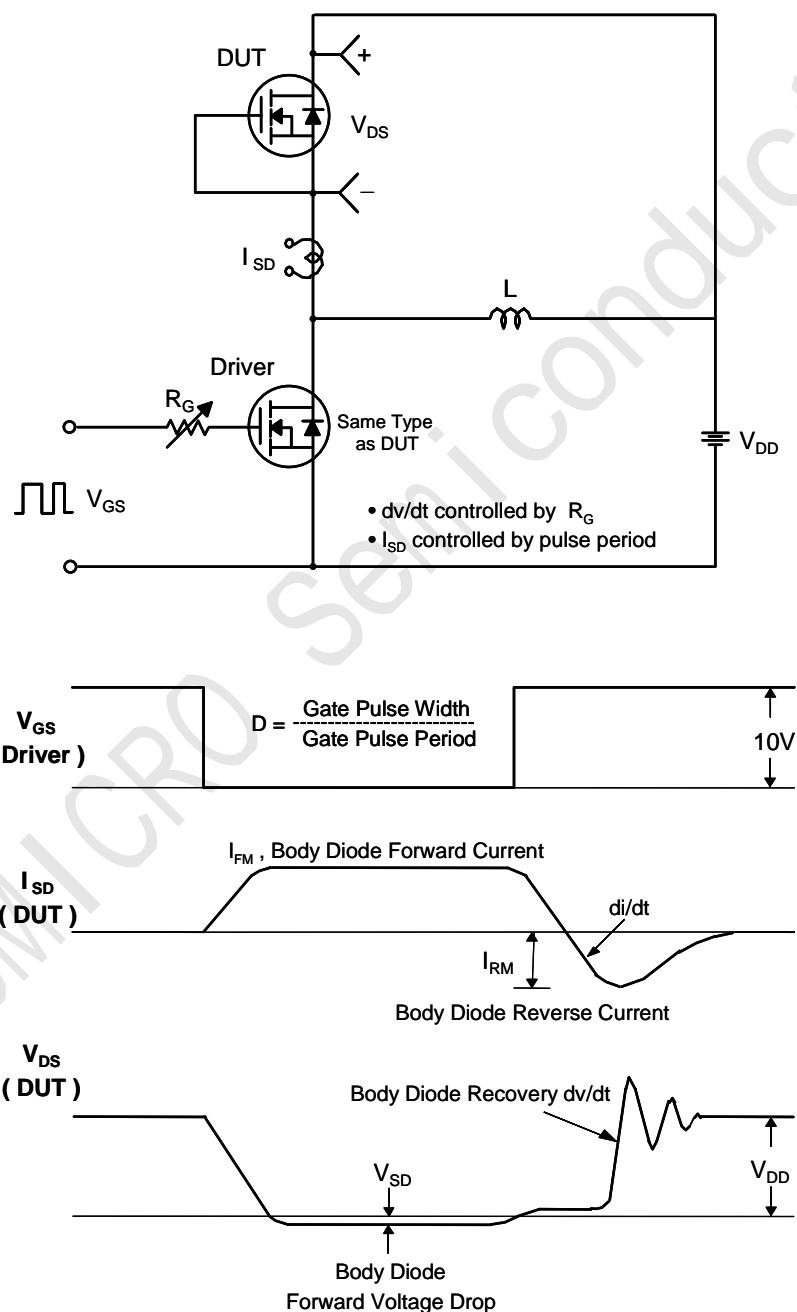


Unclamped Inductive Switching Test Circuit & Waveforms



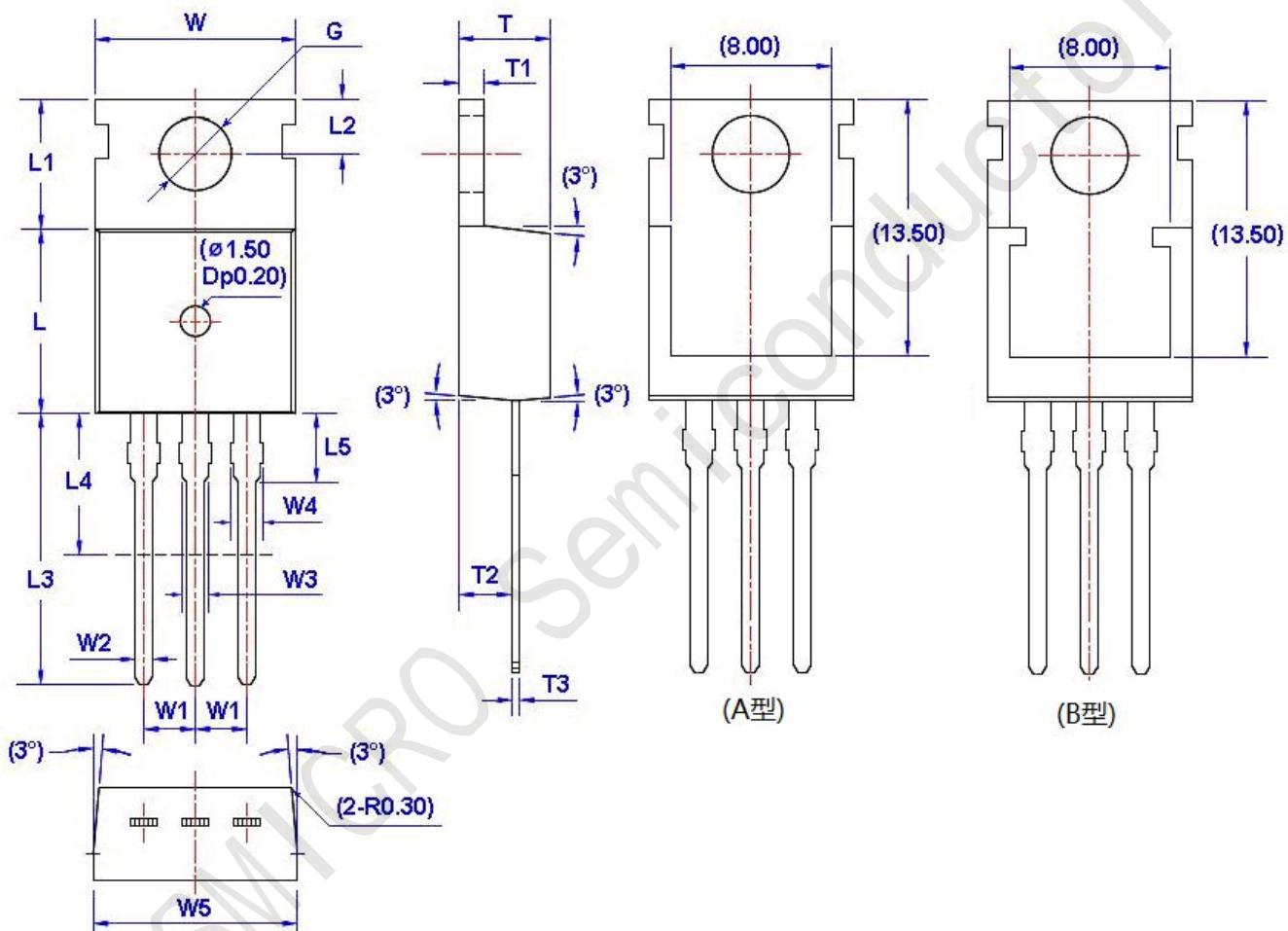
Typical Characteristics (Continued)

Peak Diode Recovery dv/dt Test Circuit & Waveforms



TO-220AB

Unit: mm



Symbol	Size		Symbol	Size		Symbol	Size		Symbol	Size	
	Min	Max		Min	Max		Min	Max		Min	Max
W	9.66	10.28	W5	9.80	10.20	L4**	6.20	6.60	T3	0.45	0.60
W1	2.54 (TYP)		L	9.00	9.40	L5	2.79	3.30	G(Φ)	3.50	3.70
W2	0.70	0.95	L1	6.40	6.80	T	4.30	4.70			
W3	1.17	1.37	L2	2.70	2.90	T1	1.15	1.40			
W4*	1.32	1.72	L3	12.70	14.27	T2	2.20	2.60			